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Application/Control No.	Applicant(s)/Patent under Reexamination
10/801,623	YUAN ET AL.
Examiner	Art Unit
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Class	Subclass	Date	Examiner
43 [°] 5	4,15,18	5/24/2005	SEF
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST: US-PGPUB, USPAT, EPO, JPO, DERWENT —see search history	5/24/2005	SEF
STN: REGISTRY, CAPLUS, BIOSISsee search history	5/25/2005	SEF
inventor name search: PALM, EAST, STN	5/25/2005	SEF
consulted 60/486,865	5/26/2005	SEF
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